

Notice of References Cited	Application/Control No. 09/873,931	Applicant(s)/Patent Under Reexamination HORNING ET AL.	
	Examiner Steven H. Rao	Art Unit 2814	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	H.H. Radamson et al., "Electrical characterization and the Strain compensastion effect and thermal stability of B-doped Si-Ge/si heterostrcutres, 1996, Semiconductor Science technology, 11 (1996) 1396-1401. <i>(copy enclosed)</i>
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